

Notice of References Cited	Application/Control No. 09/886,362	Applicant(s)/Patent Under Reexamination INNES ET AL.	
	Examiner Jonathan G. Sterrett	Art Unit 3623	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Merriam-Websters Collegiate Dictionary, 10th edition, Copyright 1997, p.1 & 746.
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